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INFORMATION DISCLOSURE CITATION <small>(Use several sheets if necessary)</small>				ATTY DOCKET NO.	APPLICATION NO.	
				X0R920030077US1		10/627,753
APPLICANT(S) Kam-Leung Lee, et al.						
FILING DATE July 28, 2003		GROUP ART UNIT 2823				
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>BR</i>	6,518,150 B1	02/11/03	Matsumoto			
<i>BR</i>	6,069,062	05/30/00	Downey			
<i>BR</i>	6,180,476 B1	01/30/01	Yu			
<i>BR</i>	6,380,053 B1	04/30/02	Komatsu			
U.S. PATENT APPLICATION PUBLICATIONS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	2003/009640-A1	05/22/03	Borland, et al.			
<i>document cannot be found</i>						
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES
						NO
<i>crossed out</i>						
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
<i>BR</i>		Article by T.H. Huang, et al.: "Influence of Fluorine Preamorphization on the Diffusion and Activation of Low-Energy Implanted Boron During Rapid Thermal Annealing", Applied Physics Letters, American Institute of Physics, NY, US Vol. 65, No. 14, October 3, 1994, pp. 1829-1831.				
<i>BR</i>		Article by S. Saito, et al.: "Defect Reduction by MeV ion Implantation for Shallow Junction Formation", Applied Physics Letters, American Institute of Physics, Vol. 63, No. 2, July 12, 1993, pp. 197-199.				
EXAMINER			DATE CONSIDERED			
<i>Brook Kebode</i>			<i>1/6/2005</i>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						

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<i>BDL</i>	6,426,278 B1	07/30/02	Nowak, et al.			
<i>BML</i>	6,087,209	07/11/00	Yeap, et al.			
<i>BML</i>	6,410,393 B1	06/25/02	Hao, et al.			

U.S. PATENT APPLICATION PUBLICATIONS

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FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
<i>BDL</i>	WO 97/42652	11/13/97	PCT				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>BDL</i>	PCT International Search Report dated October 8, 2004.
<i>BML</i>	PCT Written Opinion of the International Searching Authority. (EPO - January 2004)

EXAMINER	DATE CONSIDERED

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